Se	arch	Notes	;

Application/Control No.	Applicant(s)/Patent under Reexamination
10/797,726	PECHANEK ET AL.
Examiner	Art Unit
Christopher B. Shin	2181

-	SEARCHED		
Class	Subclass	Date	Examiner
710	22-35, 308	9/11/2006	CBS
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
710	22, 308	2/3/2007	cs
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
PALM for Double Patenting	9/11/2006	CBS
EAST (EPO JPO, USPGPUB, USPAT, USOCR, IBMTDB)	9/11/2006	CBS
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